

Course Number & Name: EEL 4310 and EEL5322 - Digital Integrated Circuits Design

Credits and Contact Hours: 3 crs; 3 classes per week of 50 minutes each

Instructor's or Course Coordinator's Name: Dr. Scott E. Thompson

Contact info Prof. Scott Thompson
535 Engineering Bldg
846-0320
Office hours: M W F 8th period days of live class
Plus e-learning discussion board (<https://lss.at.ufl.edu/>)
(plus additional office hours arranged via email thompson@ece.ufl.edu)

Cadence help TBD

TA TBD

Textbook Title, Author, and Year:

Title - Introduction to Microelectronic Fabrication (**Required**)

Author - Richard C. Jaeger

Publication date and edition - 2nd Edition, Modular Series on Solid State Devices, Volume 5, Prentice Hall

dISBN Number - 0-201-44494-7

Title - Digital Integrated Circuits, A Design Perspective (**Required**)

Author - Jan. M. Rabaey, A. Chandrakasan, and B.Nikolic

Publication date and edition - 2nd Edition, Prentice Hall

ISBN Number - 0-13-090996-3, 2003

Computer and Software required: Workstations with CADENCE Design system on campus, off-campus can use XWindows or X-terminal on a high-speed internet link to UF Campus Computers, or can use equivalent IC design software

a. Supplemental Material:

Specific Course Information

a. Catalog Description: Fabrication, Layout, Analysis and design of digital and circuits using MOS Transistors

b. Prerequisites or Co-requisites: EEL 3396, EEL 3308

c. Required, Elective, or Selected Elective (Table 5-1):

Specific Goals for the Course

a. Specific Outcomes of Instruction:

This course focuses on analysis and design of modern digital circuits. Silicon technology and transistors are introduced and described from a digital point of view, and the performance of various circuits is derived and estimated. CMOS digital circuits will be designed and analyzed. Students will layout and design digital complex circuits using layout software and SPICE and cover advanced topics such as manufacturing variations.

b. Explicitly indicate which of the student outcomes listed in Criterion 3 or any other outcomes are addressed by this course:

EE2, a, c, e, I, k

Topics to Be Coverer

Week 1: Moore's Law, History and Future of Computing, Chipworks tear down of a mobile computer (iPhone and iPad), Jaeger Chapter 1.

Week 2: Design rules, Chap. 2 .1, 2.2 and 2.3 of Rabaey, 1.2, 1.3.1

Week 3: Contacts and Interconnects Chap. 7 Jaeger and handouts. MOS Process Integration Chap. 9 of Jaeger and State of the art CMOS planar and FinFET SOC process flow: 28nm, 20nm, 14nm, 10nm Logic Technologies and advanced layout issues: Optical Proximity correction and Restrictive Design Rules

Week 4-5: What is VLSI, **Cadence Design Training**, Statistics Review, and Introduction to micro fabrication with emphasis on process variation Chap. 5 .1, 5.2, 5.3, 5.4 of Jaeger, plus handouts and Chipworks reverse engineering reports

Week 6-7: CMOS Logic, DRAM, NAND, CMOS image sensor chips fabrication, bit cell or pixel cell, and array architecture Chap. 8.7 of Jaeger and Chapter 2.2 Rabaey plus handouts

Week 8-9: Layout Layers and X-sections Design Rules, Resistance, Capacitance, MOSFET Chap. 4.1 to 4.3 and Chap. 3.3 of Rabaey and 9.2, 9.3 Jaeger

Week 10: MOS Transistors, CMOS Inverters, Chap. 3.3 and Chap. 5 of Rabaey

Week 11: CMOS Inverters, Chap. 5 of Rabaey

Week 12: Combination Logic, Compound Gates, Chap. 6 of Rabaey

Week 13: Transmission Gates, Memory, Chap. 6 and Chap. 12 of Rabaey

Week 14: Memory, Pseudo NMOS, Pass Trans. Logic, Chap. 6 of Rabaey

Week 14: Pre-charge Logic, and Dynamic Logic, Chap. 6 of Rabaey

Week 15: Domino Logic, Logic Comparison, Noise Chap. 6 of Rabaey

- Grading:

-

- 70% in Class exams

- 10% Test 1 : Monday Sept 22

- 15% Test 2 Oct. 20

- 15% Test 3 Nov.. 17

- 30% Comprehensive Final Exam as scheduled by college

- 10% Homework

- 20% Projects (1,2 3) Final Class Project Due Dec 6

- Test and projects and homework different for EEL 4310 and EEL5322

- No exam make-up unless valid excuse. All valid excuses must be approved by the Professor.

- Final Grading Scale

-

- $\geq 90\% \rightarrow A$; $\geq 86.67\% \rightarrow A-$; $\geq 83.33\% \rightarrow B+$; $\geq 80\% \rightarrow B$; $\geq 76.67\% \rightarrow B-$; $\geq 73.33\% \rightarrow C+$; $\geq 70\% \rightarrow C$; $\geq 66.67\% \rightarrow C-$; $\geq 63.33\% \rightarrow D+$; $\geq 60\% \rightarrow D$; $\geq 56.67\% \rightarrow D-$; $< 56.67\% \rightarrow E$

- Attendance: Due to quantity and research nature of material, it is important to make every attempt to attend class or watch all class lectures (when possible).